

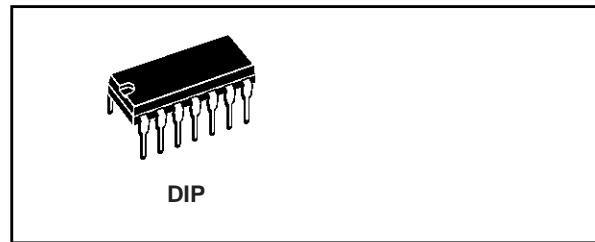


上海双岭电子有限公司

CC4012

DUAL 4 INPUT NAND GATE

- PROPAGATION DELAY TIME
 $t_{PD} = 60\text{ns}$ (Typ.) at $V_{DD} = 10\text{V}$
- BUFFERED INPUTS AND OUTPUTS
- STANDARDIZED SYMMETRICAL OUTPUT CHARACTERISTICS
- QUIESCENT CURRENT SPECIFIED UP TO 20V
- 5V, 10V AND 15V PARAMETRIC RATINGS
- INPUT LEAKAGE CURRENT
 $I_I = 100\text{nA}$ (MAX) AT $V_{DD} = 18\text{V}$ $T_A = 25^\circ\text{C}$
- 100% TESTED FOR QUIESCENT CURRENT
- MEETS ALL REQUIREMENTS OF JEDEC JESD13B "STANDARD SPECIFICATIONS FOR DESCRIPTION OF B SERIES CMOS DEVICES"



ORDER CODES

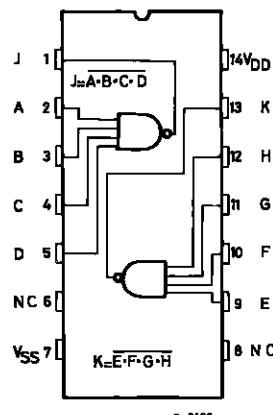
PACKAGE	TUBE	T & R
DIP	CC4012	

DESCRIPTION

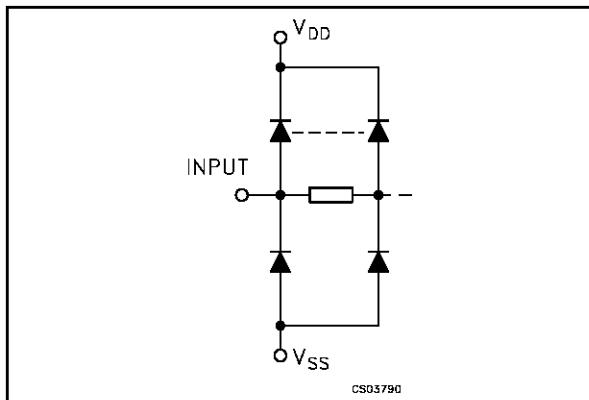
The CC4012 is a monolithic integrated circuit fabricated in Metal Oxide Semiconductor technology available in DIP and SOP packages. The CC4012 DUAL 4-INPUT NAND GATE provides the system designer with direct

implementation of the NAND function and supplement the existing family of CMOS gates. All inputs and outputs are buffered.

PIN CONNECTION



INPUT EQUIVALENT CIRCUIT



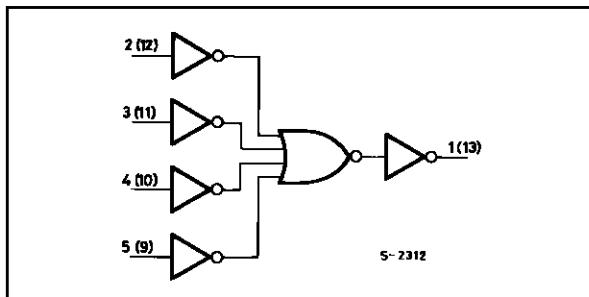
PIN DESCRIPTION

PIN No	SYMBOL	NAME AND FUNCTION
6, 8	NC	Not Connected
2, 3, 4, 5	A, B, C, D	Data Inputs
9, 10, 11, 12	E, F, G, H	Data Inputs
1, 13	J, K	Data Outputs
7	V _{SS}	Negative Supply Voltage
14	V _{DD}	Positive Supply Voltage

TRUTH TABLE

INPUTS		OUTPUTS
A, B, C, D	E, F, G, H	J, K
L	L	H
L	H	H
H	L	H
H	H	L

LOGIC DIAGRAM



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{DD}	Supply Voltage	-0.5 to +20	V
V _I	DC Input Voltage	-0.5 to V _{DD} + 0.5	V
I _I	DC Input Current	± 10	mA
P _D	Power Dissipation per Package	200	mW
	Power Dissipation per Output Transistor	100	mW
T _{op}	Operating Temperature	-55 to +125	°C
T _{stg}	Storage Temperature	-65 to +150	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied.

All voltage values are referred to V_{SS} pin voltage.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Value	Unit
V _{DD}	Supply Voltage	3 to 18	V
V _I	Input Voltage	0 to V _{DD}	V
T _{op}	Operating Temperature	-55 to 125	°C

DC SPECIFICATIONS

Symbol	Parameter	Test Condition				Value						Unit	
		V_I (V)	V_O (V)	I_{IO} (μ A)	V_{DD} (V)	$T_A = 25^\circ C$			$-40 \text{ to } 85^\circ C$		$-55 \text{ to } 125^\circ C$		
						Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
I_L	Quiescent Current	0/5			5		0.01	0.25		7.5		7.5	μA
		0/10			10		0.01	0.5		15		15	
		0/15			15		0.01	1		30		30	
		0/18			18		0.02	5		150		150	
V_{OH}	High Level Output Voltage	0/5		<1	5	4.95			4.95		4.95		V
		0/10		<1	10	9.95			9.95		9.95		
		0/15		<1	15	14.95			14.95		14.95		
V_{OL}	Low Level Output Voltage	5/0		<1	5		0.05			0.05		0.05	V
		10/0		<1	10		0.05			0.05		0.05	
		15/0		<1	15		0.05			0.05		0.05	
V_{IH}	High Level Input Voltage	0.5/4.5	<1	5	3.5				3.5		3.5		V
		1/9	<1	10	7				7		7		
		1.5/13.5	<1	15	11				11		11		
V_{IL}	Low Level Input Voltage	4.5/0.5	<1	5				1.5		1.5		1.5	V
		9/1	<1	10				3		3		3	
		13.5/1.5	<1	15				4		4		4	
I_{OH}	Output Drive Current	0/5	2.5	<1	5	-1.36	-3.2		-1.15		-1.1		mA
		0/5	4.6	<1	5	-0.44	-1		-0.36		-0.36		
		0/10	9.5	<1	10	-1.1	-2.6		-0.9		-0.9		
		0/15	13.5	<1	15	-3.0	-6.8		-2.4		-2.4		
I_{OL}	Output Sink Current	0/5	0.4	<1	5	0.44	1		0.36		0.36		mA
		0/10	0.5	<1	10	1.1	2.6		0.9		0.9		
		0/15	1.5	<1	15	3.0	6.8		2.4		2.4		
I_I	Input Leakage Current	0/18	Any Input	18			$\pm 10^{-5}$	± 0.1		± 1		± 1	μA
C_I	Input Capacitance		Any Input				5	7.5					pF

The Noise Margin for both "1" and "0" level is: 1V min. with $V_{DD}=5V$, 2V min. with $V_{DD}=10V$, 2.5V min. with $V_{DD}=15V$

DYNAMIC ELECTRICAL CHARACTERISTICS ($T_{amb} = 25^\circ C$, $C_L = 50pF$, $R_L = 200K\Omega$, $t_r = t_f = 20 \text{ ns}$)

Symbol	Parameter	Test Condition				Value (*)			Unit	
		V_{DD} (V)				Min.	Typ.	Max.		
t_{PLH} t_{PHL}	Propagation Delay Time	5						125	250	ns
		10						60	120	
		15						45	90	
t_{TLH} t_{THL}	Output Transition Time	5						100	200	ns
		10						50	100	
		15						40	80	

(*) Typical temperature coefficient for all V_{DD} value is 0.3 %/ $^\circ C$.